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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

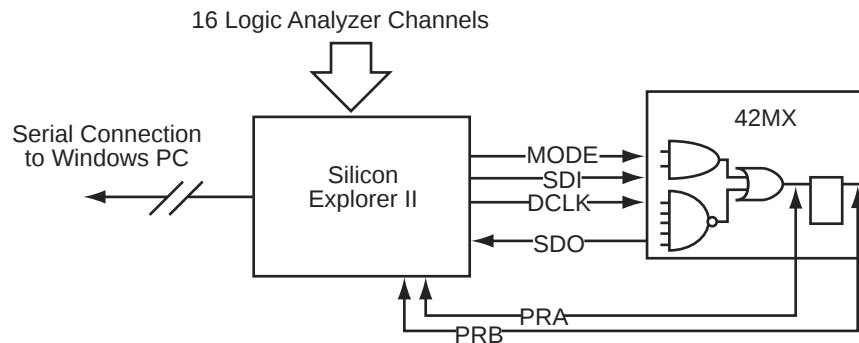
Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	104
Number of Gates	14000
Voltage - Supply	3V ~ 3.6V, 4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TC)
Package / Case	176-LQFP
Supplier Device Package	176-TQFP (24x24)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a42mx09-tq176m

Figure 13 • Silicon Explorer II Setup with 42MX**Table 8 • Device Configuration Options for Probe Capability**

Security Fuse(s) Programmed	Mode	PRA, PRB ¹	SDI, SDO, DCLK ¹
No	LOW	User I/Os ²	User I/Os ²
No	HIGH	Probe Circuit Outputs	Probe Circuit Inputs
Yes	–	Probe Circuit Secured	Probe Circuit Secured

1. Avoid using SDI, SDO, DCLK, PRA and PRB pins as input or bidirectional ports. Since these pins are active during probing, input signals will not pass through these pins and may cause contention.
2. If no user signal is assigned to these pins, they will behave as unused I/Os in this mode. See the Pin Descriptions, page 83 for information on unused I/O pins

3.4.7 Design Consideration

It is recommended to use a series 70 Ω termination resistor on every probe connector (SDI, SDO, MODE, DCLK, PRA and PRB). The 70 Ω series termination is used to prevent data transmission corruption during probing and reading back the checksum.

3.4.8 IEEE Standard 1149.1 Boundary Scan Test (BST) Circuitry

42MX24 and 42MX36 devices are compatible with IEEE Standard 1149.1 (informally known as Joint Testing Action Group Standard or JTAG), which defines a set of hardware architecture and mechanisms for cost-effective board-level testing. The basic MX boundary-scan logic circuit is composed of the TAP (test access port), TAP controller, test data registers and instruction register (Figure 14, page 18). This circuit supports all mandatory IEEE 1149.1 instructions (EXTEST, SAMPLE/PRELOAD and BYPASS) and some optional instructions. Table 9, page 18 describes the ports that control JTAG testing, while Table 10, page 18 describes the test instructions supported by these MX devices.

Each test section is accessed through the TAP, which has four associated pins: TCK (test clock input), TDI and TDO (test data input and output), and TMS (test mode selector).

The TAP controller is a four-bit state machine. The '1's and '0's represent the values that must be present at TMS at a rising edge of TCK for the given state transition to occur. IR and DR indicate that the instruction register or the data register is operating in that state.

The TAP controller receives two control inputs (TMS and TCK) and generates control and clock signals for the rest of the test logic architecture. On power-up, the TAP controller enters the Test-Logic-Reset state. To guarantee a reset of the controller from any of the possible states, TMS must remain high for five TCK cycles.

42MX24 and 42MX36 devices support three types of test data registers: bypass, device identification, and boundary scan. The bypass register is selected when no other register needs to be accessed in a device. This speeds up test data transfer to other devices in a test data path. The 32-bit device identification register is a shift register with four fields (lowest significant byte (LSB), ID number, part number and version). The boundary-scan register observes and controls the state of each I/O pin.

3.4.9 JTAG Mode Activation

The JTAG test logic circuit is activated in the Designer software by selecting **Tools > Device Selection**. This brings up the Device Selection dialog box as shown in the following figure. The JTAG test logic circuit can be enabled by clicking the “Reserve JTAG Pins” check box. The following table explains the pins' behavior in either mode.

Figure 15 • Device Selection Wizard

Table 11 • Boundary Scan Pin Configuration and Functionality

Reserve JTAG	Checked	Unchecked
TCK	BST input; must be terminated to logical HIGH or LOW to avoid floating	User I/O
TDI, TMS	BST input; may float or be tied to HIGH	User I/O
TDO	BST output; may float or be connected to TDI of another device	User I/O

3.4.10 TRST Pin and TAP Controller Reset

An active reset (TRST) pin is not supported; however, MX devices contain power-on circuitry that resets the boundary scan circuitry upon power-up. Also, the TMS pin is equipped with an internal pull-up resistor. This allows the TAP controller to remain in or return to the Test-Logic-Reset state when there is no input or when a logical 1 is on the TMS pin. To reset the controller, TMS must be HIGH for at least five TCK cycles.

3.4.11 Boundary Scan Description Language (BSDL) File

Conforming to the IEEE Standard 1149.1 requires that the operation of the various JTAG components be documented. The BSDL file provides the standard format to describe the JTAG components that can be used by automatic test equipment software. The file includes the instructions that are supported, instruction bit pattern, and the boundary-scan chain order. For an in-depth discussion on BSDL files, see the *BSDL Files Format Description* application note.

BSDL files are grouped into two categories - generic and device-specific. The generic files assign all user I/Os as inouts. Device-specific files assign user I/Os as inputs, outputs or inouts.

Generic files for MX devices are available on the Microsemi SoC Product Group's website:

<http://www.microsemi.com/soc/techdocs/models/bsdl.html>.

3.5 Development Tool Support

The MX family of FPGAs is fully supported by Libero® Integrated Design Environment (IDE). Libero IDE is a design management environment, seamlessly integrating design tools while guiding the user through the design flow, managing all design and log files, and passing necessary design data among tools. Libero IDE allows users to integrate both schematic and HDL synthesis into a single flow and verify the entire design in a single environment. Libero IDE includes SynplifyPro from Synopsys, ModelSim® HDL Simulator from Mentor Graphics® and Viewdraw.

Libero IDE includes place-and-route and provides a comprehensive suite of backend support tools for FPGA development, including timing-driven place-and-route, and a world-class integrated static timing analyzer and constraints editor.

Note: *Stresses beyond those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Devices should not be operated outside the recommended operating conditions.

Table 14 • Recommended Operating Conditions

Parameter	Commercial	Industrial	Military	Units
Temperature Range*	0 to +70	–40 to +85	–55 to +125	°C
VCC (40MX)	4.75 to 5.25	4.5 to 5.5	4.5 to 5.5	V
VCCA (42MX)	4.75 to 5.25	4.5 to 5.5	4.5 to 5.5	V
VCCI (42MX)	4.75 to 5.25	4.5 to 5.5	4.5 to 5.5	V

Note: * Ambient temperature (T_A) is used for commercial and industrial grades; case temperature (T_C) is used for military grades.

3.7.1 5 V TTL Electrical Specifications

The following tables show 5 V TTL electrical specifications.

Table 15 • 5V TTL Electrical Specifications

Symbol	Parameter	Commercial		Commercial -F		Industrial		Military		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
VOH ¹	IOH = –10 mA	2.4		2.4						V
	IOH = –4 mA					3.7		3.7		V
VOL ¹	IOL = 10 mA		0.5		0.5					V
	IOL = 6 mA					0.4		0.4		V
VIL		–0.3	0.8	–0.3	0.8	–0.3	0.8	–0.3	0.8	V
VIH (40MX)		2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	V
VIH (42MX) ²		2.0	VCCI + 0.3	2.0	VCCI + 0.3	2.0	VCCI + 0.3	2.0	VCCI + 0.3	V
IIL	VIN = 0.5 V		–10		–10		–10		–10	μA
IIH	VIN = 2.7 V		–10		–10		–10		–10	μA
Input Transition Time, T_R and T_F			500		500		500		500	ns
C _{IO} I/O Capacitance			10		10		10		10	pF
Standby Current, ICC ³	A40MX02, A40MX04		3		25		10		25	mA
	A42MX09		5		25		25		25	mA
	A42MX16		6		25		25		25	mA
	A42MX24, A42MX36		20		25		25		25	mA
Low power mode Standby Current	42MX devices only		0.5		ICC – 5.0		ICC – 5.0		ICC – 5.0	mA
IIO, I/O source sink current	Can be derived from the <i>IBIS model</i> (http://www.microsemi.com/soc/techdocs/models/ibis.html)									

1. Only one output tested at a time. VCC/VCCI = min

2. VIH(Min) is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V

3.9.1 Mixed 5.0V/3.3V Electrical Specifications

Table 22 • Mixed 5.0V/3.3V Electrical Specifications

Symbol	Parameter	Commercial		Commercial –F		Industrial		Military		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
VOH ¹	IOH = –10 mA	2.4		2.4						V
	IOH = –4 mA					2.4		2.4		V
VOL ¹	IOL = 10 mA	0.5		0.5						V
	IOL = 6 mA					0.4		0.4		V
VIL		–0.3	0.8	–0.3	0.8	–0.3	0.8	–0.3	0.8	V
VIH ²		2.0	VCCA + 0.3	2.0	VCCA + 0.3	2.0	VCCA + 0.3	2.0	VCCA + 0.3	V
IL	VIN = 0.5 V	–10		–10		–10		–10		μA
IH	VIN = 2.7 V	–10		–10		–10		–10		μA
Input Transition Time, TR and TF		500		500		500		500		ns
C _{IO} I/O Capacitance		10		10		10		10		pF
Standby Current, ICC ³	A42MX09	5		25		25		25		mA
	A42MX16	6		25		25		25		mA
	A42MX24, A42MX36	20		25		25		25		mA
Low Power Mode Standby Current		0.5		ICC – 5.0		ICC – 5.0		ICC – 5.0		mA
I/O I/O source sink current Can be derived from the <i>IBIS model</i> (http://www.microsemi.com/soc/techdocs/models/ibis.html)										

1. Only one output tested at a time. VCCI = min.

2. VIH(Min) is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V

3. All outputs unloaded. All inputs = VCCI or GND

3.9.2 Output Drive Characteristics for 5.0 V PCI Signaling

MX PCI device I/O drivers were designed specifically for high-performance PCI systems. Figure 16, page 28 shows the typical output drive characteristics of the MX devices. MX output drivers are compliant with the PCI Local Bus Specification.

Table 23 • DC Specification (5.0 V PCI Signaling)¹

Symbol	Parameter	Condition	PCI		MX		Units
			Min.	Max.	Min.	Max.	
VCCI	Supply Voltage for I/Os		4.75	5.25	4.75	5.25 ²	V
VIH ³	Input High Voltage		2.0	VCC + 0.5	2.0	VCCI + 0.3	V
VIL	Input Low Voltage		–0.5	0.8	–0.3	0.8	V
IIH	Input High Leakage Current	VIN = 2.7 V		70	—	10	μA
IIL	Input Low Leakage Current	VIN=0.5 V		–70	—	–10	μA
VOH	Output High Voltage	IOUT = –2 mA IOUT = –6 mA	2.4		3.84		V
VOL	Output Low Voltage	IOUT = 3 mA, 6 mA		0.55	—	0.33	V

3.9.3 Output Drive Characteristics for 3.3 V PCI Signaling

Table 25 • DC Specification (3.3 V PCI Signaling)¹

Symbol	Parameter	Condition	PCI		MX		Units
			Min.	Max.	Min.	Max.	
VCCI	Supply Voltage for I/Os		3.0	3.6	3.0	3.6 ²	V
VIH	Input High Voltage		0.5	VCC + 0.5	0.5	VCCI + 0.3	V
VIL	Input Low Voltage		−0.5	0.8	−0.3	0.8	V
IIH	Input High Leakage Current	VIN = 2.7 V		70		10	μA
IIL	Input Leakage Current			−70		−10	μA
VOH	Output High Voltage	IOUT = −2 mA	0.9		3.3		V
VOL	Output Low Voltage	IOUT = 3 mA, 6 mA		0.1		0.1 VCCI	V
CIN	Input Pin Capacitance			10		10	pF
CLK	CLK Pin Capacitance		5	12		10	pF
L _{PIN}	Pin Inductance			20		< 8 nH ³	nH

1. PCI Local Bus Specification, Version 2.1, Section 4.2.2.1.

2. Maximum rating for VCCI −0.5 V to 7.0V.

3. Dependent upon the chosen package. PCI recommends QFP and BGA packaging to reduce pin inductance and capacitance.

Table 26 • AC Specifications for (3.3 V PCI Signaling)*

Symbol	Parameter	Condition	PCI		MX		Units
			Min.	Max.	Min.	Max.	
ICL	Low Clamp Current	−5 < VIN ≤ −1	−25 + (VIN + 1) / 0.015		−60	−10	mA
Slew (r)	Output Rise Slew Rate	0.2 V to 0.6 V load	1	4	1.8	2.8	V/ns
Slew (f)	Output Fall Slew Rate	0.6 V to 0.2 V load	1	4	2.8	4.0	V/ns

Note: *PCI Local Bus Specification, Version 2.1, Section 4.2.2.2.

A sample calculation of the absolute maximum power dissipation allowed for a TQ176 package at commercial temperature and still air is given in the following equation

$$\text{MaximumPowerAllowed} = \frac{\text{Max} \cdot \text{junction temp} \cdot (^\circ\text{C}) - \text{Max} \cdot \text{ambient temp} \cdot (^\circ\text{C})}{\theta_{ja} (^\circ\text{C/W})} = \frac{150^\circ\text{C} - 70^\circ\text{C}}{(28^\circ\text{C})/\text{W}} = 2.86\text{W}$$

EQ 5

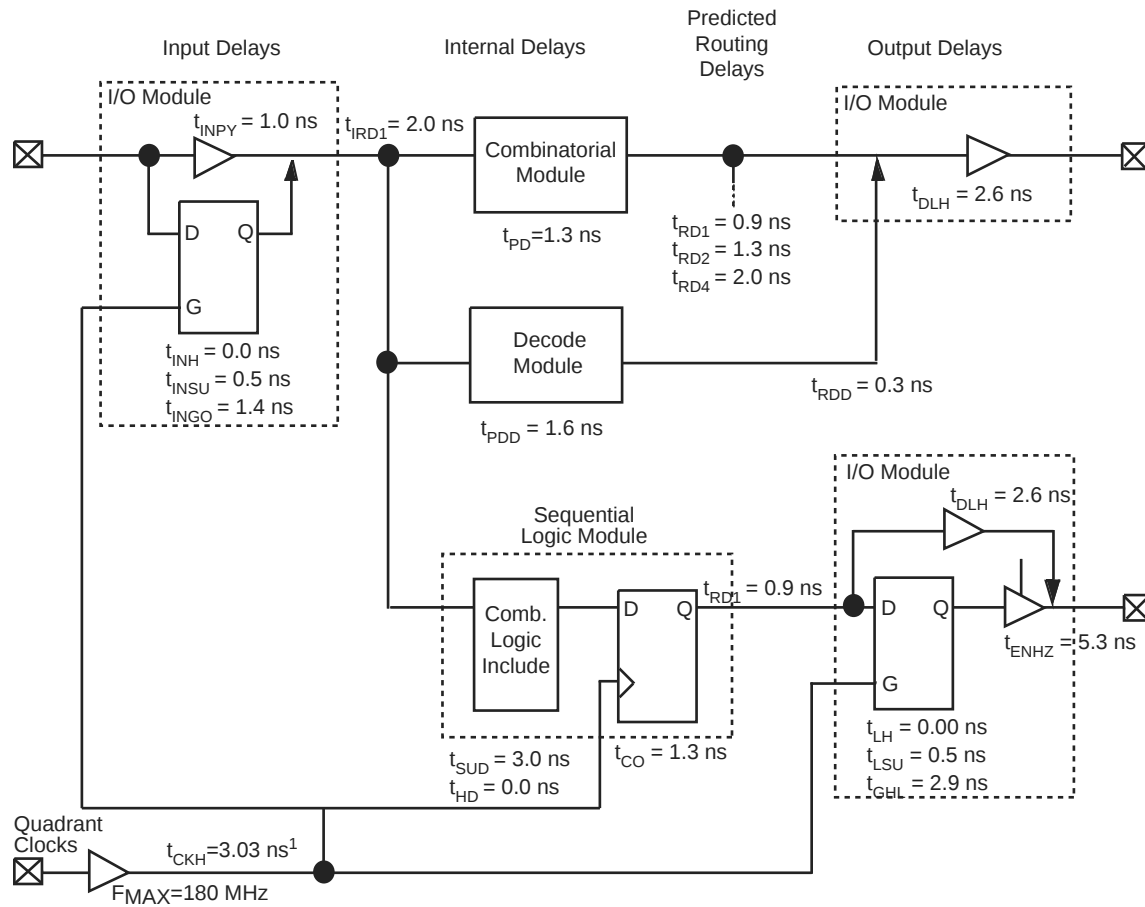
The maximum power dissipation for military-grade devices is a function of θ_{jc} . A sample calculation of the absolute maximum power dissipation allowed for CQFP 208-pin package at military temperature and still air is given in the following equation

$$\text{MaximumPowerAllowed} = \frac{\text{Max} \cdot \text{junction temp} \cdot (^\circ\text{C}) - \text{Max} \cdot \text{ambient temp} \cdot (^\circ\text{C})}{\theta_{jc} (^\circ\text{C/W})} = \frac{150^\circ\text{C} - 125^\circ\text{C}}{(6.3^\circ\text{C})/\text{W}} = 3.97\text{W}$$

EQ 6

Table 27 • Package Thermal Characteristics

Plastic Packages	Pin Count	θ_{jc}	θ_{ja}			Units
			Still Air	1.0 m/s 200 ft/min.	2.5 m/s 500 ft/min.	
Plastic Quad Flat Pack	100	12.0	27.8	23.4	21.2	$^\circ\text{C/W}$
Plastic Quad Flat Pack	144	10.0	26.2	22.8	21.1	$^\circ\text{C/W}$
Plastic Quad Flat Pack	160	10.0	26.2	22.8	21.1	$^\circ\text{C/W}$
Plastic Quad Flat Pack	208	8.0	26.1	22.5	20.8	$^\circ\text{C/W}$
Plastic Quad Flat Pack	240	8.5	25.6	22.3	20.8	$^\circ\text{C/W}$
Plastic Leaded Chip Carrier	44	16.0	20.0	24.5	22.0	$^\circ\text{C/W}$
Plastic Leaded Chip Carrier	68	13.0	25.0	21.0	19.4	$^\circ\text{C/W}$
Plastic Leaded Chip Carrier	84	12.0	22.5	18.9	17.6	$^\circ\text{C/W}$
Thin Plastic Quad Flat Pack	176	11.0	24.7	19.9	18.0	$^\circ\text{C/W}$
Very Thin Plastic Quad Flat Pack	80	12.0	38.2	31.9	29.4	$^\circ\text{C/W}$
Very Thin Plastic Quad Flat Pack	100	10.0	35.3	29.4	27.1	$^\circ\text{C/W}$
Plastic Ball Grid Array	272	3.0	18.3	14.9	13.9	$^\circ\text{C/W}$
Ceramic Packages						
Ceramic Pin Grid Array	132	4.8	25.0	20.6	18.7	$^\circ\text{C/W}$
Ceramic Quad Flat Pack	208	2.0	22.0	19.8	18.0	$^\circ\text{C/W}$
Ceramic Quad Flat Pack	256	2.0	20.0	16.5	15.0	$^\circ\text{C/W}$

Figure 19 • 42MX Timing Model (Logic Functions Using Quadrant Clocks)

Note: 1. Load-dependent

Note: 2. Values are shown for A42MX36 –3 at 5.0 V worst-case commercial conditions

Table 33 • Timing Parameters for 33 MHz PCI

Symbol	Parameter	PCI		A42MX24		A42MX36		Units
		Min.	Max.	Min.	Max.	Min.	Max.	
$t_{SU(PTP)}$	Input Set-Up Time to CLK—Point-to-Point	10, 12 ²	—	1.5	—	1.5	—	ns
t_H	Input Hold to CLK	0	—	0	—	0	—	ns

1. TOFF is system dependent. MX PCI devices have 7.4 ns turn-off time, reflection is typically an additional 10 ns.
2. REQ# and GNT# are point-to-point signals and have different output valid delay and input setup times than do bussed signals. GNT# has a setup of 10; REW# has a setup of 12.

3.11.6.1 Timing Characteristics

The following tables list the timing characteristics.

**Table 34 • A40MX02 Timing Characteristics (Nominal 5.0 V Operation)
(Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Propagation Delays												
t _{PD1}	Single Module		1.2		1.4		1.6		1.9		2.7	ns
t _{PD2}	Dual-Module Macros		2.7		3.1		3.5		4.1		5.7	ns
t _{CO}	Sequential Clock-to-Q		1.2		1.4		1.6		1.9		2.7	ns
t _{GO}	Latch G-to-Q		1.2		1.4		1.6		1.9		2.7	ns
t _{RS}	Flip-Flop (Latch) Reset-to-Q		1.2		1.4		1.6		1.9		2.7	ns
Logic Module Predicted Routing Delays ¹												
t _{RD1}	FO = 1 Routing Delay		1.3		1.5		1.7		2.0		2.8	ns
t _{RD2}	FO = 2 Routing Delay		1.8		2.1		2.4		2.8		3.9	ns
t _{RD3}	FO = 3 Routing Delay		2.3		2.7		3.0		3.6		5.0	ns
t _{RD4}	FO = 4 Routing Delay		2.9		3.3		3.7		4.4		6.1	ns
t _{RD8}	FO = 8 Routing Delay		4.9		5.7		6.5		7.6		10.6	ns
Logic Module Sequential Timing ²												
t _{SUD}	Flip-Flop (Latch) Data Input Set-Up	3.1		3.5		4.0		4.7		6.6		ns
t _{HD} ³	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up	3.1		3.5		4.0		4.7		6.6		ns
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	3.3		3.8		4.3		5.0		7.0		ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	3.3		3.8		4.3		5.0		7.0		ns
t _A	Flip-Flop Clock Input Period	4.8		5.6		6.3		7.5		10.4		ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency (FO = 128)		181		168		154		134		80	MHz

Table 36 • A40MX04 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{ENLZ}	Enable Pad LOW to Z		5.9		6.8		7.7		9.0		12.6	ns
d _{TLH}	Delta LOW to HIGH		0.02		0.02		0.03		0.03		0.04	ns/pF
d _{THL}	Delta HIGH to LOW		0.03		0.03		0.03		0.04		0.06	ns/pF

Table 44 • A42MX36 Timing Characteristics (Nominal 5.0 V Operation)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
TTL Output Module Timing ⁵ (Continued)												
t _{ENLZ}	Enable Pad LOW to Z		4.9		5.5		6.2		7.3		10.2	ns
t _{GLH}	G-to-Pad HIGH		2.9		3.3		3.7		4.4		6.1	ns
t _{GHL}	G-to-Pad LOW		2.9		3.3		3.7		4.4		6.1	ns
t _{LSU}	I/O Latch Output Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t _{LH}	I/O Latch Output Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		5.7		6.3		7.1		8.4		11.8	ns
t _{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.8		8.6		9.8		11.5		16.1	ns
d _{TLH}	Capacitive Loading, LOW to HIGH		0.07		0.08		0.09		0.10		0.14	ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW		0.07		0.08		0.09		0.10		0.14	ns/pF

Table 48 • PL68

PL68		
Pin Number	A40MX02 Function	A40MX04 Function
61	I/O	I/O
62	I/O	I/O
63	I/O	I/O
64	I/O	I/O
65	I/O	I/O
66	GND	GND
67	I/O	I/O
68	I/O	I/O

Figure 40 • PL84

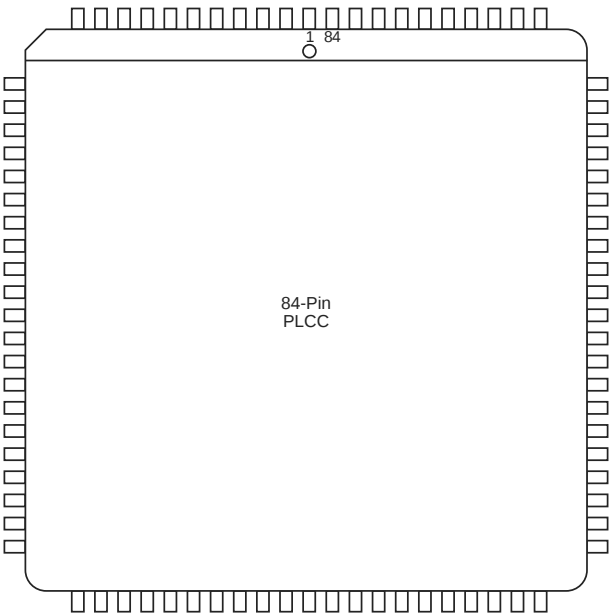


Table 49 • PL84

PL84				
Pin Number	A40MX04 Function	A42MX09 Function	A42MX16 Function	A42MX24 Function
1	I/O	I/O	I/O	I/O
2	I/O	CLKB, I/O	CLKB, I/O	CLKB, I/O
3	I/O	I/O	I/O	I/O
4	VCC	PRB, I/O	PRB, I/O	PRB, I/O
5	I/O	I/O	I/O	WD, I/O
6	I/O	GND	GND	GND
7	I/O	I/O	I/O	I/O
8	I/O	I/O	I/O	WD, I/O
9	I/O	I/O	I/O	WD, I/O

Table 49 • PL84

PL84				
Pin Number	A40MX04 Function	A42MX09 Function	A42MX16 Function	A42MX24 Function
10	I/O	DCLK, I/O	DCLK, I/O	DCLK, I/O
11	I/O	I/O	I/O	I/O
12	NC	MODE	MODE	MODE
13	I/O	I/O	I/O	I/O
14	I/O	I/O	I/O	I/O
15	I/O	I/O	I/O	I/O
16	I/O	I/O	I/O	I/O
17	I/O	I/O	I/O	I/O
18	GND	I/O	I/O	I/O
19	GND	I/O	I/O	I/O
20	I/O	I/O	I/O	I/O
21	I/O	I/O	I/O	I/O
22	I/O	VCCA	VCCI	VCCI
23	I/O	VCCI	VCCA	VCCA
24	I/O	I/O	I/O	I/O
25	VCC	I/O	I/O	I/O
26	VCC	I/O	I/O	I/O
27	I/O	I/O	I/O	I/O
28	I/O	GND	GND	GND
29	I/O	I/O	I/O	I/O
30	I/O	I/O	I/O	I/O
31	I/O	I/O	I/O	I/O
32	I/O	I/O	I/O	I/O
33	VCC	I/O	I/O	I/O
34	I/O	I/O	I/O	TMS, I/O
35	I/O	I/O	I/O	TDI, I/O
36	I/O	I/O	I/O	WD, I/O
37	I/O	I/O	I/O	I/O
38	I/O	I/O	I/O	WD, I/O
39	I/O	I/O	I/O	WD, I/O
40	GND	I/O	I/O	I/O
41	I/O	I/O	I/O	I/O
42	I/O	I/O	I/O	I/O
43	I/O	VCCA	VCCA	VCCA
44	I/O	I/O	I/O	WD, I/O
45	I/O	I/O	I/O	WD, I/O
46	VCC	I/O	I/O	WD, I/O

Table 50 • PQ 100

PQ100				
Pin Number	A40MX02 Function	A40MX04 Function	A42MX09 Function	A42MX16 Function
56	VCC	VCC	I/O	I/O
57	I/O	I/O	GND	GND
58	I/O	I/O	I/O	I/O
59	I/O	I/O	I/O	I/O
60	I/O	I/O	I/O	I/O
61	I/O	I/O	I/O	I/O
62	I/O	I/O	I/O	I/O
63	GND	GND	I/O	I/O
64	I/O	I/O	LP	LP
65	I/O	I/O	VCCA	VCCA
66	I/O	I/O	VCCI	VCCI
67	I/O	I/O	VCCA	VCCA
68	I/O	I/O	I/O	I/O
69	VCC	VCC	I/O	I/O
70	I/O	I/O	I/O	I/O
71	I/O	I/O	I/O	I/O
72	I/O	I/O	GND	GND
73	I/O	I/O	I/O	I/O
74	I/O	I/O	I/O	I/O
75	I/O	I/O	I/O	I/O
76	I/O	I/O	I/O	I/O
77	NC	NC	I/O	I/O
78	NC	NC	I/O	I/O
79	NC	NC	SDI, I/O	SDI, I/O
80	NC	I/O	I/O	I/O
81	NC	I/O	I/O	I/O
82	NC	I/O	I/O	I/O
83	I/O	I/O	I/O	I/O
84	I/O	I/O	GND	GND
85	I/O	I/O	I/O	I/O
86	GND	GND	I/O	I/O
87	GND	GND	PRA, I/O	PRA, I/O
88	I/O	I/O	I/O	I/O
89	I/O	I/O	CLKA, I/O	CLKA, I/O
90	CLK, I/O	CLK, I/O	VCCA	VCCA
91	I/O	I/O	I/O	I/O
92	MODE	MODE	CLKB, I/O	CLKB, I/O

Figure 42 • PQ144

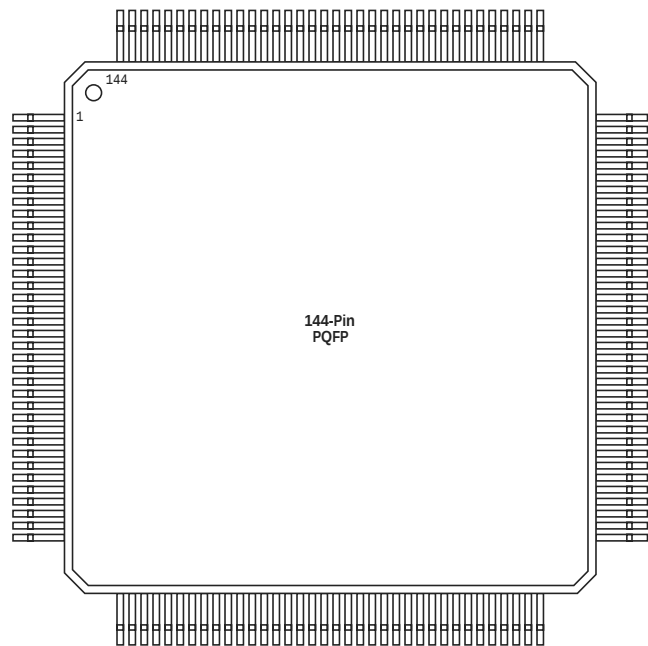


Table 51 • PQ144

PQ144	
Pin Number	A42MX09 Function
1	I/O
2	MODE
3	I/O
4	I/O
5	I/O

Table 53 • PQ208

PQ208			
Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
169	I/O	WD, I/O	WD, I/O
170	I/O	I/O	I/O
171	NC	I/O	QCLKD, I/O
172	I/O	I/O	I/O
173	I/O	I/O	I/O
174	I/O	I/O	I/O
175	I/O	I/O	I/O
176	I/O	WD, I/O	WD, I/O
177	I/O	WD, I/O	WD, I/O
178	PRA, I/O	PRA, I/O	PRA, I/O
179	I/O	I/O	I/O
180	CLKA, I/O	CLKA, I/O	CLKA, I/O
181	NC	I/O	I/O
182	NC	VCCI	VCCI
183	VCCA	VCCA	VCCA
184	GND	GND	GND
185	I/O	I/O	I/O
186	CLKB, I/O	CLKB, I/O	CLKB, I/O
187	I/O	I/O	I/O
188	PRB, I/O	PRB, I/O	PRB, I/O
189	I/O	I/O	I/O
190	I/O	WD, I/O	WD, I/O
191	I/O	WD, I/O	WD, I/O
192	I/O	I/O	I/O
193	NC	I/O	I/O
194	NC	WD, I/O	WD, I/O
195	NC	WD, I/O	WD, I/O
196	I/O	I/O	QCLKC, I/O
197	NC	I/O	I/O
198	I/O	I/O	I/O
199	I/O	I/O	I/O
200	I/O	I/O	I/O
201	NC	I/O	I/O
202	VCCI	VCCI	VCCI
203	I/O	WD, I/O	WD, I/O
204	I/O	WD, I/O	WD, I/O
205	I/O	I/O	I/O

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
237	GND
238	MODE
239	VCCA
240	GND

Figure 46 • VQ80

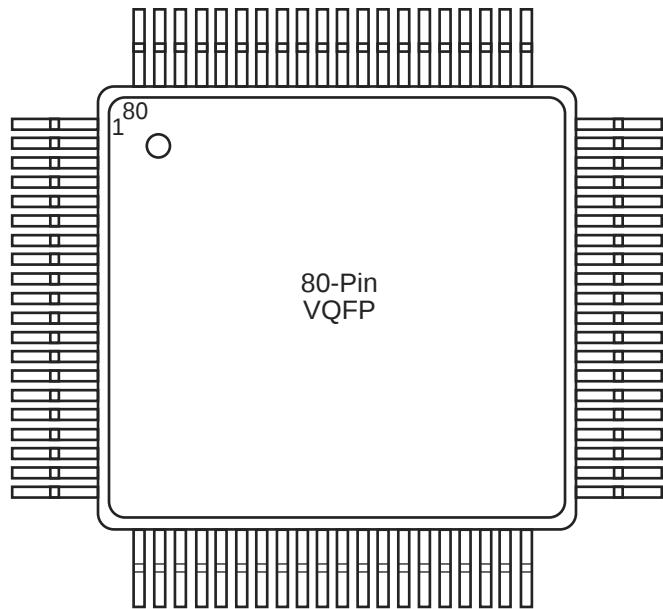


Table 55 • VQ80

VQ80		
Pin Number	A40MX02 Function	A40MX04 Function
1	I/O	I/O
2	NC	I/O
3	NC	I/O
4	NC	I/O
5	I/O	I/O
6	I/O	I/O
7	GND	GND
8	I/O	I/O
9	I/O	I/O
10	I/O	I/O
11	I/O	I/O
12	I/O	I/O

Table 55 • VQ80

VQ80		
Pin Number	A40MX02 Function	A40MX04 Function
49	I/O	I/O
50	CLK, I/O	CLK, I/O
51	I/O	I/O
52	MODE	MODE
53	VCC	VCC
54	NC	I/O
55	NC	I/O
56	NC	I/O
57	SDI, I/O	SDI, I/O
58	DCLK, I/O	DCLK, I/O
59	PRA, I/O	PRA, I/O
60	NC	NC
61	PRB, I/O	PRB, I/O
62	I/O	I/O
63	I/O	I/O
64	I/O	I/O
65	I/O	I/O
66	I/O	I/O
67	I/O	I/O
68	GND	GND
69	I/O	I/O
70	I/O	I/O
71	I/O	I/O
72	I/O	I/O
73	I/O	I/O
74	VCC	VCC
75	I/O	I/O
76	I/O	I/O
77	I/O	I/O
78	I/O	I/O
79	I/O	I/O
80	I/O	I/O

Table 57 • TQ176

TQ176			
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
158	CLKB, I/O	CLKB, I/O	CLKB, I/O
159	I/O	I/O	I/O
160	PRB, I/O	PRB, I/O	PRB, I/O
161	NC	I/O	WD, I/O
162	I/O	I/O	WD, I/O
163	I/O	I/O	I/O
164	I/O	I/O	I/O
165	NC	NC	WD, I/O
166	NC	I/O	WD, I/O
167	I/O	I/O	I/O
168	NC	I/O	I/O
169	I/O	I/O	I/O
170	NC	VCCI	VCCI
171	I/O	I/O	WD, I/O
172	I/O	I/O	WD, I/O
173	NC	I/O	I/O
174	I/O	I/O	I/O
175	DCLK, I/O	DCLK, I/O	DCLK, I/O
176	I/O	I/O	I/O

Figure 49 • CQ208

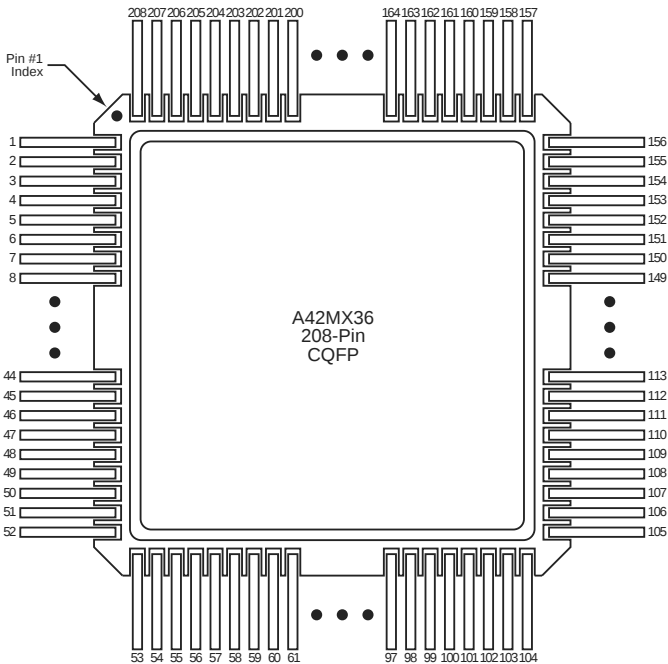


Table 59 • CQ256

CQ256	
Pin Number	A42MX36 Function
96	VCCA
97	GND
98	GND
99	I/O
100	I/O
101	I/O
102	I/O
103	I/O
104	I/O
105	WD, I/O
106	WD, I/O
107	I/O
108	I/O
109	WD, I/O
110	WD, I/O
111	I/O
112	QCLKA, I/O
113	I/O
114	GND
115	I/O
116	I/O
117	I/O
118	I/O
119	VCCI
120	I/O
121	WD, I/O
122	WD, I/O
123	I/O
124	I/O
125	I/O
126	I/O
127	GND
128	NC
129	NC
130	NC
131	GND
132	I/O

Table 60 • BG272

BG272	
Pin Number	A42MX36 Function
M10	GND
M11	GND
M12	GND
M17	I/O
M18	I/O
M19	I/O
M20	I/O
N1	I/O
N2	I/O
N3	I/O
N4	VCCI
N17	VCCI
N18	I/O
N19	I/O
N20	I/O
P1	I/O
P2	I/O
P3	I/O
P4	VCCA
P17	I/O
P18	I/O
P19	I/O
P20	I/O
R1	I/O
R2	I/O
R3	I/O
R4	VCCI
R17	VCCI
R18	I/O
R19	I/O
R20	I/O
T1	I/O
T2	I/O
T3	I/O
T4	I/O
T17	VCCA
T18	I/O